

FDD6N25 / FDU6N25 250V N-Channel MOSFET

Features

- 4.4A, 250V, $R_{DS(on)} = 1.1\Omega @V_{GS} = 10 V$
- Low gate charge (typical 4.5 nC)
- Low C_{rss} (typical 5 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability



These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

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This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies and active power factor correction.



Absolute Maximum Ratings

Symbol	Parameter		FDD6N25 / FDU6N25	Unit	
V _{DSS}	Drain-Source Voltage	e		250	V
I _D	Drain Current	- Continuous (T _C = 25°C) - Continuous (T _C = 100°C)	4.4 2.6	A A	
I _{DM}	Drain Current	- Pulsed (Note 1)		18	А
V _{GSS}	Gate-Source voltage			±30	V
E _{AS}	Single Pulsed Avala	nche Energy	(Note 2)	45	mJ
I _{AR}	Avalanche Current		(Note 1)	4.4	А
E _{AR}	Repetitive Avalanche Energy (Note 1)		(Note 1)	5	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		(Note 3)	4.5	V/ns
P _D	Power Dissipation $(T_C = 25^{\circ}C)$ - Derate above $25^{\circ}C$		50 0.4	W W/°C	
T _{J,} T _{STG}	Operating and Stora	Operating and Storage Temperature Range		-55 to +150	°C
Τ _L	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds		300	°C	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Unit
$R_{ extsf{ heta}JC}$	Thermal Resistance, Junction-to-Case		2.5	°C/W
R_{\thetaJA}	Thermal Resistance, Junction-to-Ambient		110	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD6N25	FDD6N25TM	D-PAK	380mm	16mm	2500
FDD6N25	FDD6N25TF	D-PAK	380mm	16mm	2000
FDU6N25	FDU6N25TU	I-PAK	-	-	70

Electrical Characteristics $T_{c} = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Conditions	Min.	Тур.	Max	Units
Off Charac	teristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250 \mu A$	250			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250μA, Referenced to 25°C		0.25		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 250V, V_{GS} = 0V$ $V_{DS} = 200V, T_{C} = 125^{\circ}C$			1 10	μΑ μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 30V, V_{DS} = 0V$			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30V, V_{DS} = 0V$			-100	nA
On Charac	teristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	3.0		5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10V, I _D = 2.2A		0.9	1.1	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = 40V, I_D = 2.2A$ (Note 4)		5.5		S
Dynamic C	haracteristics					•
C _{iss}	Input Capacitance	$V_{DS} = 25V, V_{GS} = 0V,$		194	250	pF
C _{oss}	Output Capacitance	f = 1.0MHz		38	50	pF
C _{rss}	Reverse Transfer Capacitance			5	8	pF
	Characteristics					
t _{d(on)}	Turn-On Delay Time	V _{DD} = 125V, I _D = 6A		10	30	ns
t _r	Turn-On Rise Time	$R_{G} = 25\Omega$		25	60	ns
t _{d(off)}	Turn-Off Delay Time			7	24	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		12	34	ns
Qg	Total Gate Charge	$V_{DS} = 200V, I_{D} = 6A$		4.5	6	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10V		1.5		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		1.8		nC
Drain-Sour	rce Diode Characteristics and Maximur	n Ratings			1	
I _S	Maximum Continuous Drain-Source Dio	de Forward Current			4.4	А
I _{SM}	Maximum Pulsed Drain-Source Diode F	orward Current			18	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0V, I_{S} = 4.4A$			1.4	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0V, I_S = 6A$		145		ns
Q _{rr}	Reverse Recovery Charge	dI _F /dt =100A/μs (Note 4)		0.55		μC

NOTES:

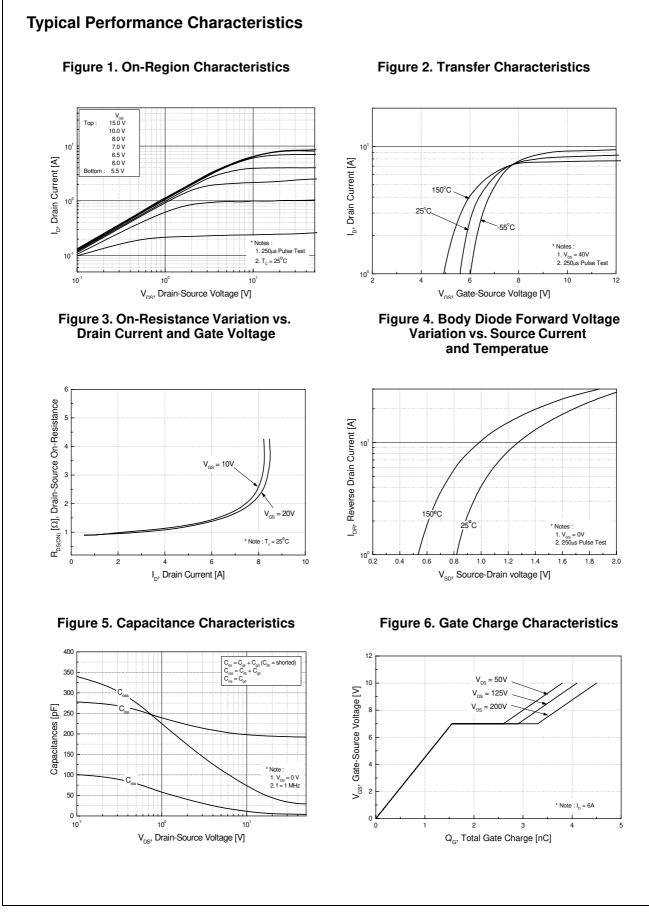
1. Repetitive Rating: Pulse width limited by maximum junction temperature

2. L = 3.7mH, I_{AS} = 4.4A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C

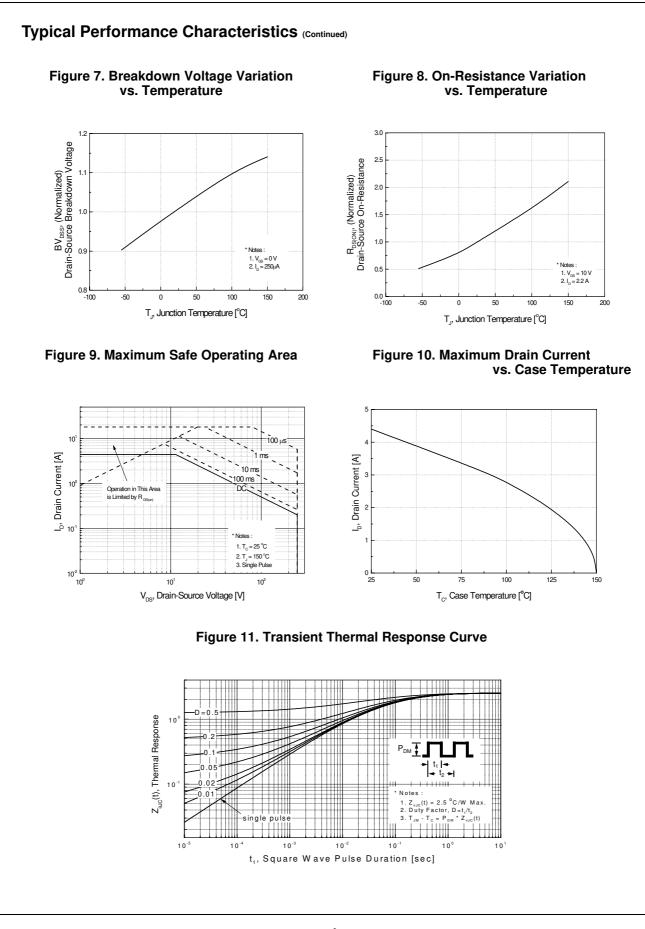
3. $I_{SD} \leq$ 4.4A, di/dt \leq 200A/µs, $V_{DD} \leq BV_{DSS},$ Starting T_J = 25°C

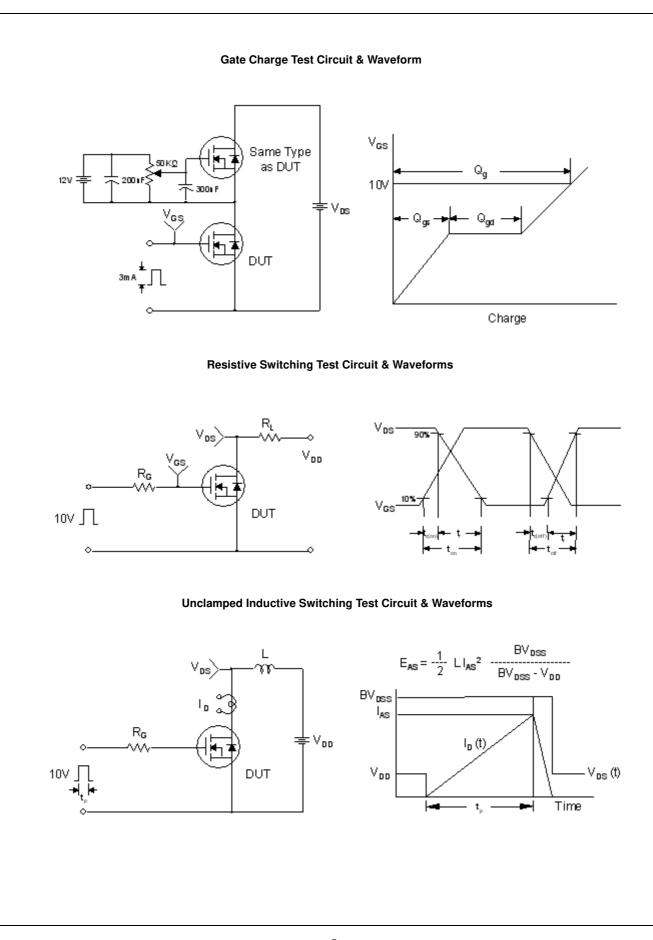
4. Pulse Test: Pulse width $\leq 300 \mu s, \, \text{Duty Cycle} \leq 2\%$

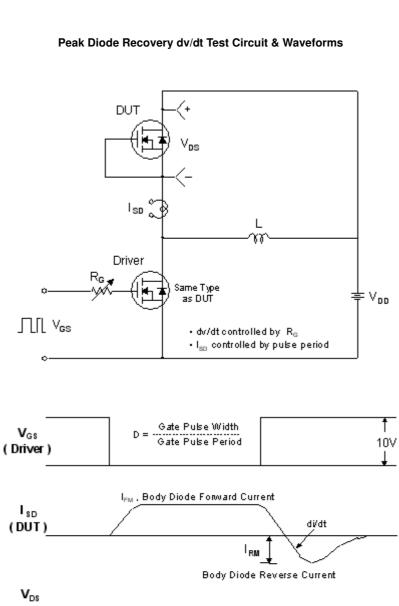
5. Essentially Independent of Operating Temperature Typical Characteristics

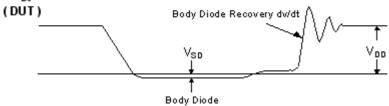


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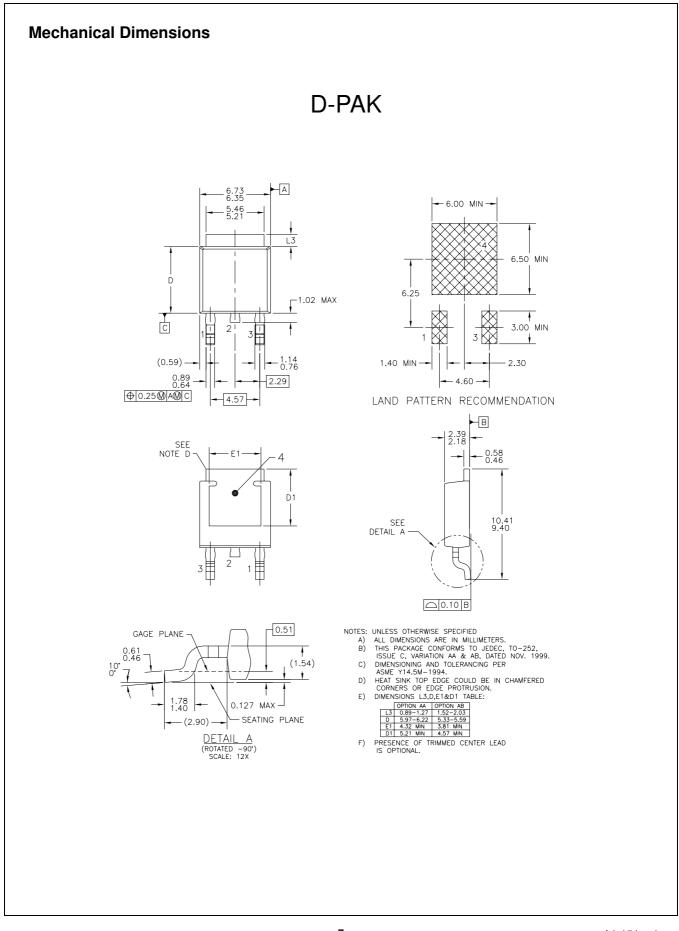


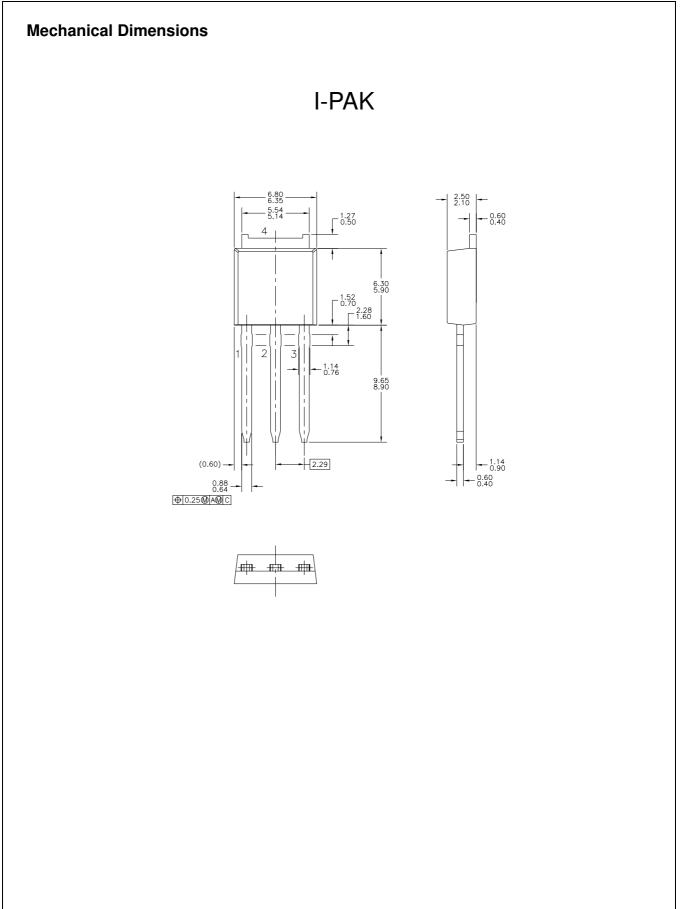






Body Diode Forward Voltage Drop







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Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild Semiconductor. The datasheet is printed for reference information only.

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FDD6N25 250V N-Channel MOSFET

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General description

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Qualification Support

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Product status/pricing/packaging



Product	Product status	Pb-free Status	Pricing*	Package type	Leads	Packing method	Package Marking Convention**

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FDD6N25TF	Full Production	Full Production	\$0.54	TO-252(DPAK)	2	TAPE REEL	Line 1: \$Y (Fairchild logo) & Z (Asm. Plant Code) &E& 3 (3-Digit Date Code) Line 2: FDD Line 3: 6N25
FDD6N25TM	Full Production	Full Production	\$0.56	TO-252(DPAK)	2		Line 1: \$Y (Fairchild logo) & Z (Asm. Plant Code) &E& 3 (3-Digit Date Code) Line 2: FDD Line 3: 6N25

* Fairchild 1,000 piece Budgetary Pricing ** A sample button will appear if the part is available through Fairchild's on-line samples program. If there is no sample button, please contact a <u>Fairchild distributor</u> to obtain samples

Ø Indicates product with Pb-free second-level interconnect. For more information click here.

Package marking information for product FDD6N25 is available. Click here for more information.

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Qualification Support

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